

<b>Search Notes</b>				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/667,004	CHAN ET AL.	
				Examiner	Art Unit	
				Frank W. Lu	1634	

<b>SEARCHED</b>			
Class	Subclass	Date	Examiner
435	6 7.1 91.1	5/12/2006	w
	183		
	283.1		
	287.1		
	287.2		
436	94		
	501		
536	231 24.3		
	2433		
	205.3		
530	300		
	350		
update		10/19/2006	w

<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
STN	DATE	EXMR
East (see attached file)	5/12/2006	w
Inventor searches update	10/19/2006	w

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner